

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BARKER ET AL.	
		Examiner Ba Huynh	Art Unit 2179	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2003/0095142	05-2003	Patrizio et al.	345/744
B	US-2002/0107872	08-2002	Hudis et al.	707/104.1
C	US-2003/0135648	07-2003	Porter, Dana J.	709/246
D	US-2003/0110073	06-2003	Briel et al.	705/10
E	US-2002/0069275	06-2002	Tindal, Glen D.	709/223
F	US-2003/0018964	01-2003	Fox et al.	717/177
G	US-2003/0095145	05-2003	Patrizio et al.	345/764
H	US-2004/0015889	01-2004	Todd et al.	717/137
I	US-2002/0140743	10-2002	DeLuca et al.	345/835
J	US-2003/0177477	09-2003	Fuchs, Daniel	717/136
K	US-2002/0091809	07-2002	Menzies et al.	709/223
L	US-6,708,074	03-2004	Chi et al.	700/121
M	US-6,252,593	06-2001	Gti, Felix Andrew	345/781

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.